



UTILITY APPLICATION

Attorney Docket No.: IMEC281.001AUS
First Named Inventor: Trudo Clarysse
Title: SYSTEM AND METHOD FOR MEASURING
PROPERTIES OF A SEMICONDUCTOR SUBSTRATE
IN A NON-DESTRUCTIVE WAY
Express Mail Label No.: EV 325 003 417

Direct all correspondence to Customer No.: 20995

Date: July 16, 2003

Page 1 of 2



Mail Stop Patent Application

United States Patent and Trademark Office

PO Box 1450

Alexandria, VA 22313-1450

The following enclosures are transmitted herewith to be filed in the patent application of:

Inventor(s):

1. Trudo Clarysse
2. Wilfried Vandervorst

APPLICATION ELEMENTS:

(X) Specification in 28 pages.

(X) Drawings in 11 sheets.

CONTINUITY INFORMATION:

Application	Relationship	Parent App. No.	Filing Date	Status
This Application	Non-Provisional of	60/397,566	July 19, 2002	Pending

(X) Incorporation by Reference. The entire disclosure of the prior application(s) is considered a part of the disclosure of the accompanying application and is hereby incorporated by reference therein.

OTHER APPLICATION PARTS:

(X) Return prepaid postcard.

UTILITY APPLICATION

Attorney Docket No.: IMEC281.001AUS

First Named Inventor: Trudo Clarysse

Title: **SYSTEM AND METHOD FOR MEASURING
PROPERTIES OF A SEMICONDUCTOR SUBSTRATE
IN A NON-DESTRUCTIVE WAY**

Express Mail Label No.: EV 325 003 417

Direct all correspondence to Customer No.: 20995

Date: July 16, 2003

Page 2 of 2

FILING FEES:

FEE CALCULATION				
FEE TYPE		FEE CODE	CALCULATION	TOTAL
Basic Utility		1001 (\$750)		\$750
Excess Claims > 20	27 - 20 = 7	1202 (\$18)	7 x 18 =	\$126
Independent > 3	6 - 3 = 3	1201 (\$84)	3 x 84 =	\$252
			TOTAL FEE DUE	\$1128

(X) The total fees calculated above will be paid at a later date.

John M. Carson
Registration No. 34,303
Attorney of Record
Customer No. 20,995
(619) 235-8550

MAIL STOP PATENT APPLICATION
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

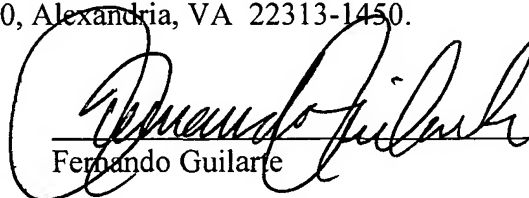
CERTIFICATE OF MAILING BY "EXPRESS MAIL"

Attorney Docket No. : IMEC281.001AUS
Applicant(s) : Clarysse et al.
For : SYSTEM AND METHOD FOR MEASURING
PROPERTIES OF A SEMICONDUCTOR
SUBSTRATE IN A NON-DESTRUCTIVE
WAY
Attorney : John M. Carson
"Express Mail"
Mailing Label No. : EV 325 003 417 US
Date of Deposit : July 16, 2003

I hereby certify that the accompanying

Transmittal letter; specification in 28 pages; 11 sheets of drawings; Return
Prepaid Postcard

are being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and are addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.



Fernando Guilarte

S:\DOCS\HZC\HZC-3746.DOC
071603